

Notice of References Cited	Application/Control No. 10/019,753	Applicant(s)/Patent Under Reexamination YAMASHITA ET AL.	
	Examiner Rip A. Lee	Art. Unit 1713	Page 1 of 1


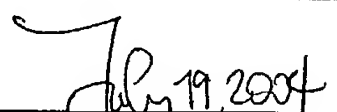
U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,066,717	01-1978	Li et al.	260/874
	B	US-4,267,086	05-1981	Pett et al.	260/28.5 R
	C	US-4,432,607	02-1984	Levy	350/96.34
	D	US-5,229,449 A	07-1993	Enomoto et al.	524/446
	E	US-5,124,240 A	06-1992	Brosius et al.	430/495
	F	US-4,326,045	04-1982	Li et al.	525/206
	G	US-4,082,820	04-1978	Li et al.	260/879
	H	US-4,105,713	08-1978	Sigwalt et al.	260/879
	I	US-4,100,226	07-1978	Li et al.	260/879
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N.	JP 11-246733 A	09-1999	Japan	---	C08L 53/00
*	O.	JP 10-231403 A	09-1998	Japan	---	C08L 25/04
	P.	JP 4-323246 A	11-1992	Japan	---	C08L 45/00
	Q	JP 2002-3706 A	01-2002	Japan	---	C08L 65/00
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	 

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.